

Advanced Information:

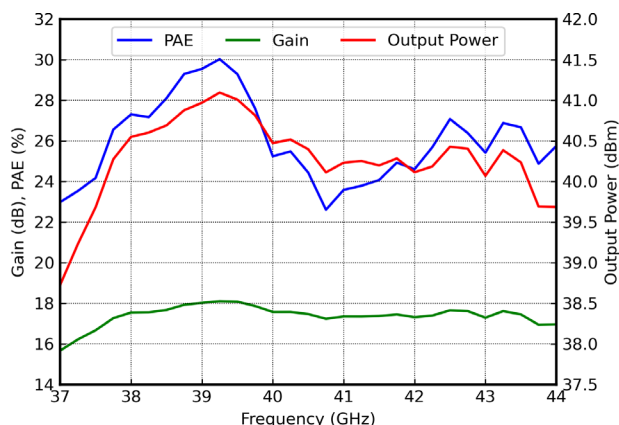
37.5 - 43.5GHz, 10W High Power Amplifier

Description

The CHA8454-99F is a three stages High Power Amplifier operating between 37.5 and 43.5GHz and providing typically 10W of saturated output power and more than 24% of Power Added Efficiency. The typical power supply is 20V/540mA (quiescent current). Thanks to a low drain voltage biasing, the CHA8454-99F provides a junction temperature below 160°C, even in saturation.

The circuit is manufactured on a space evaluated GaN-on-SiC HEMT process and is available in bare die form.

It is firstly dedicated to space, military and telecom applications and well suited for a wide range of microwave applications and systems.



Specifications

TB = +25°C, Vd = +20V, CW mode (TB : Die Backside Temperature)

Symbol	Parameter	Min	Typ	Max	Unit
Freq	Frequency range	37.5		43.5	GHz
Gain	Linear Gain		24		dB
Pout	Saturated Output Power		40.5		dBm
PAE	Power Added Efficiency		25		%
NPR	Noise Power Ratio at Pout = 35.5dBm (40MHz Modulation Bandwidth)		19		dBc
S11	Input Return Loss		-12		dB
S22	Output Return Loss		-8		dB
IDq	Quiescent Drain bias current		540		mA
Vd	Drain voltage		20		V

These values are representative of on-board measurements as defined on the drawing in paragraph "Recommended assembly plan".

Absolute Maximum Ratings ⁽¹⁾

TB = +25°C

Symbol	Parameter	Values	Unit
Vd	Drain bias voltage	27	V
IDq	Quiescent Drain bias current (without RF signal)	800	mA
Vg	Gate bias voltage	-7 to -1	V
Pin	Maximum Input Power	32	dBm

⁽¹⁾ Operation of this device above any one of these parameters may cause permanent damage.

Recommended Operating Range ^{(2), (3)}

Symbol	Parameter	Values	Unit
Vd	Drain bias voltage	18 to 25	V
IDq	Quiescent Drain bias current (without RF signal)	100 to 540	mA
Vg	Gate bias voltage	-5 to -2.5	V
Tj	Maximum Junction temperature ⁽⁴⁾	200	°C
Pin	Maximum Input Power	32	dBm

⁽²⁾ Electrical performance are defined for specified test conditions

⁽³⁾ Electrical performance are not guaranteed over all recommended operating conditions

⁽⁴⁾ See Device thermal performance section

Temperature Range

T _B	Operating temperature range at MMIC backside level	-40 to +85	°C
T _{stg}	Storage temperature range	-55 to +150	°C

Typical Bias Conditions**TB = +25°C**

Symbol	Pad N°	Parameter	Values	Unit
Vg	3, 5, 7, 25, 27, 29	Gate voltage tuned for IDq~560mA	-3.1	V
Vd	9, 11, 13, 19, 21, 23	Drain Voltage	20	V

“Power ON” sequence

1. Bias HPA gate voltage at Vg close to Vpinch-off (Vg~-5V)
2. Set Vd bias voltage to 0V: Id=0mA
3. Apply Vd bias voltage, Vd = 20V: Id=0mA
4. Increase Vg up to quiescent bias drain current IDq=540mA
5. Apply RF input Power

“Power OFF” sequence

1. Turn off RF input power
2. Bias HPA Gate voltage at Vg~-5V: Id=0mA
3. Decrease Vd bias voltage down to 0V
4. Turn Vg bias voltage to 0V

Device thermal performance

All the figures given in this section are obtained assuming that the device is only cooled down by conduction through the thermal pad (no convection mode considered).

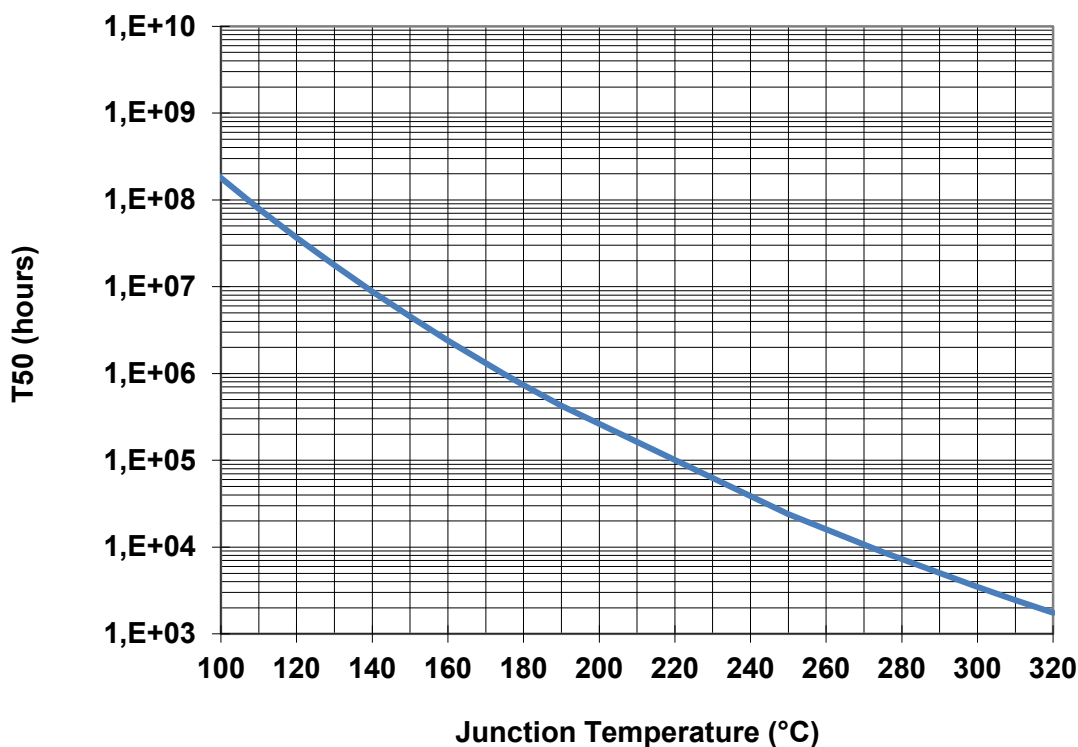
The temperature is monitored at the chip back-side interface (TB).

For nominal operating, the system maximum temperature must be adjusted in order to guarantee that the Junction Temperature remains below the maximum value specified in the Recommended Operating Ratings table.

Therefore, the system PCB must be designed to comply with this requirement.

Thermal Resistance ⁽¹⁾	R_{th_eq}	Pin at max PAE TB = 85°C, Vd = 20V, IDq = 560 mA, Pin = 26 dBm, Freq = 40GHz, Pdiss = 32 W	1.99	°C/W
Junction Temperature	T_j		147	°C
Median Life	T50		4E6	Hrs
Thermal Resistance ⁽¹⁾	R_{th_eq}	TB = 85°C, Vd = 20V, IDq = 560 mA, Pin = 30 dBm, Freq = 40GHz, Pdiss = 39 W	2.61	°C/W
Junction Temperature	T_j		186	°C
Median Life	T50		4E5	Hrs

¹ Thermal resistance measured at the backside of the chip

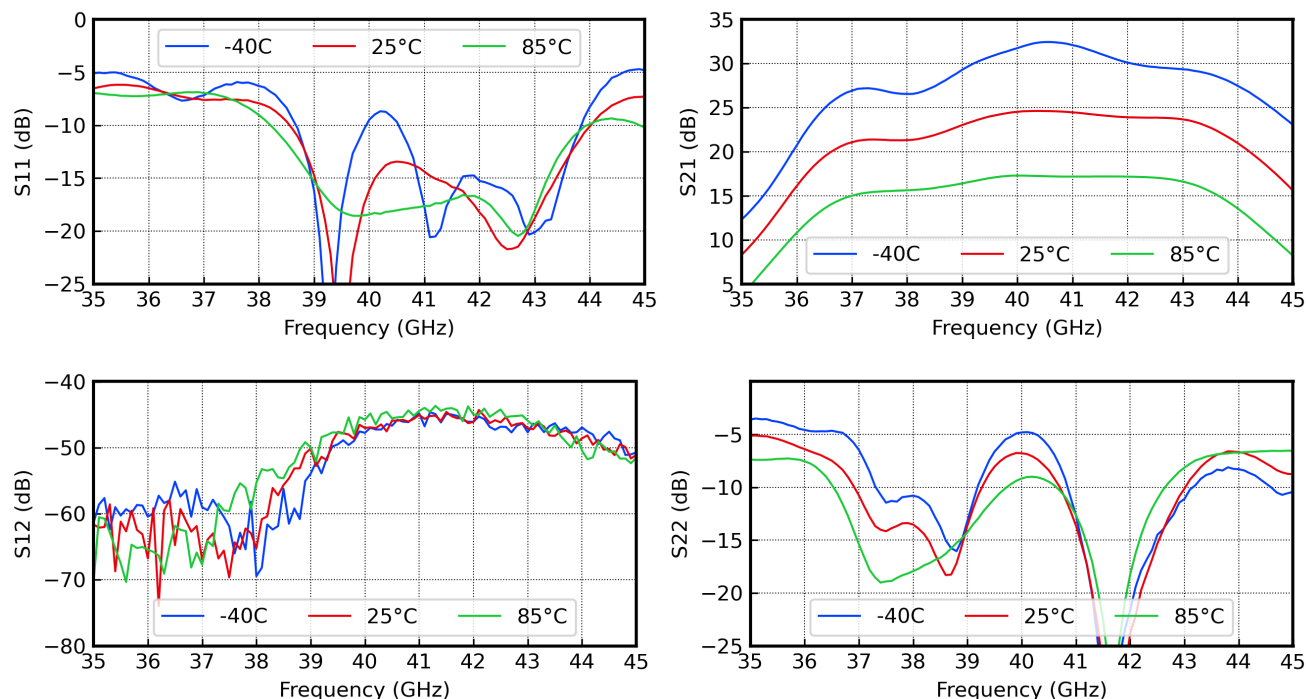


Typical Board Measurements : Small Signal Performance

Measurements reference is at the connector plane for S11 and S22, and de-embedded at the wire-bondings planes of the RF lines for S21 and S12

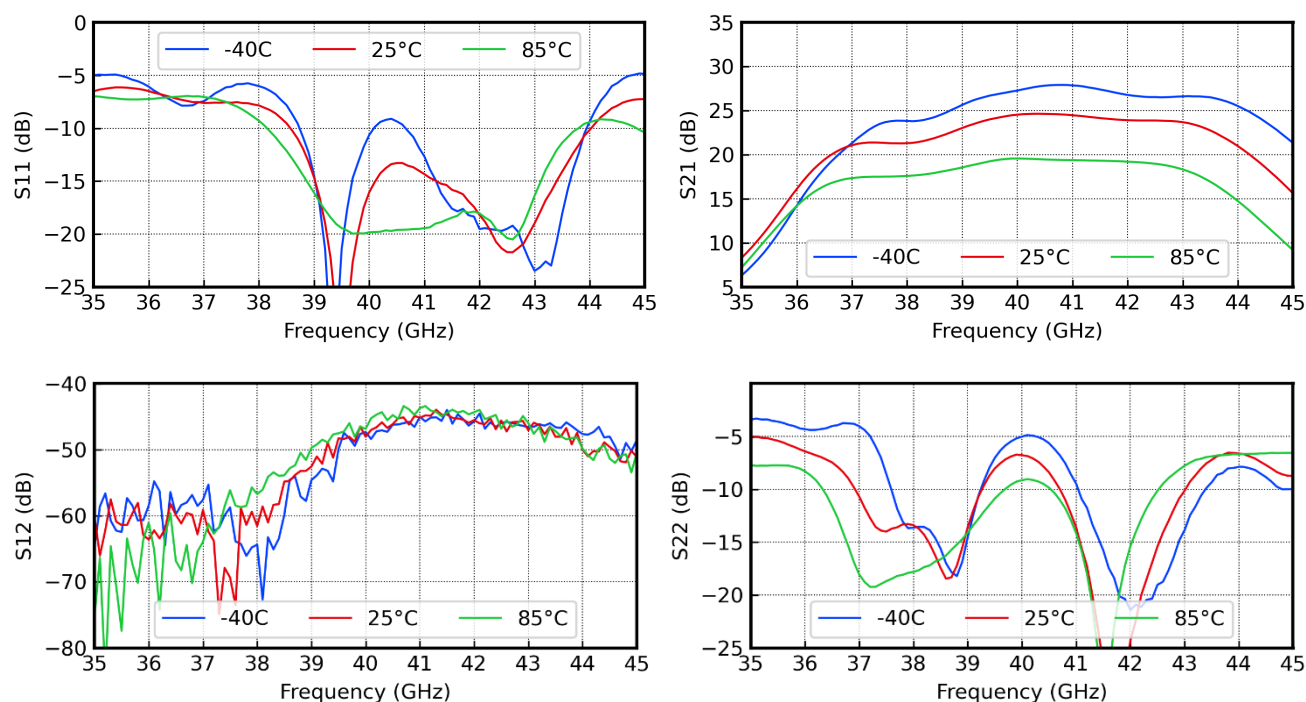
S Parameters versus frequency and temperature

Test conditions : $V_D = 20V$, $ID_q = 560mA$, $T_B = -40^\circ C / 25^\circ C / 85^\circ C$



S Parameters versus frequency and temperature

Test conditions : $V_D = 20V$, V_G fixed at $ID_q = 560mA$ at $25^\circ C$ T_B , $T_B = -40^\circ C / 25^\circ C / 85^\circ C$

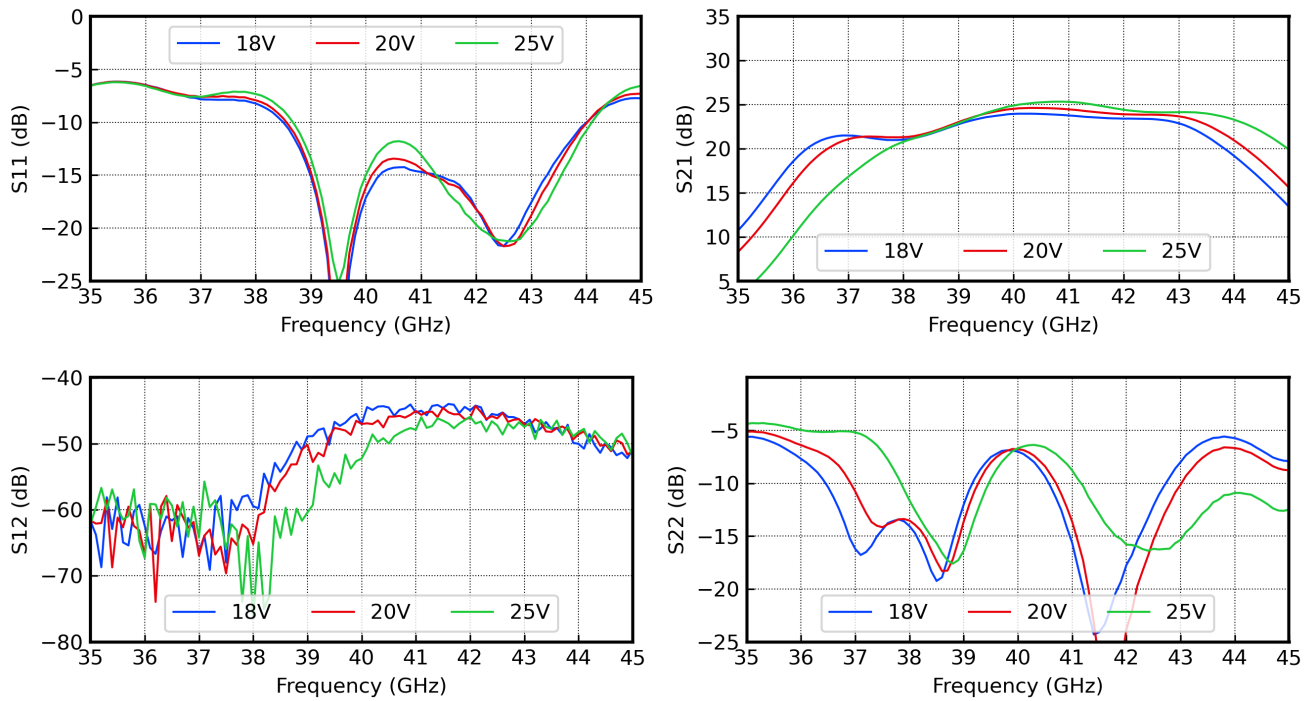


Typical Board Measurements : Small Signal Performance

Measurements reference is at the connector plane for S11 and S22, and de-embedded at the wire-bondings planes of the RF lines for S21 and S12

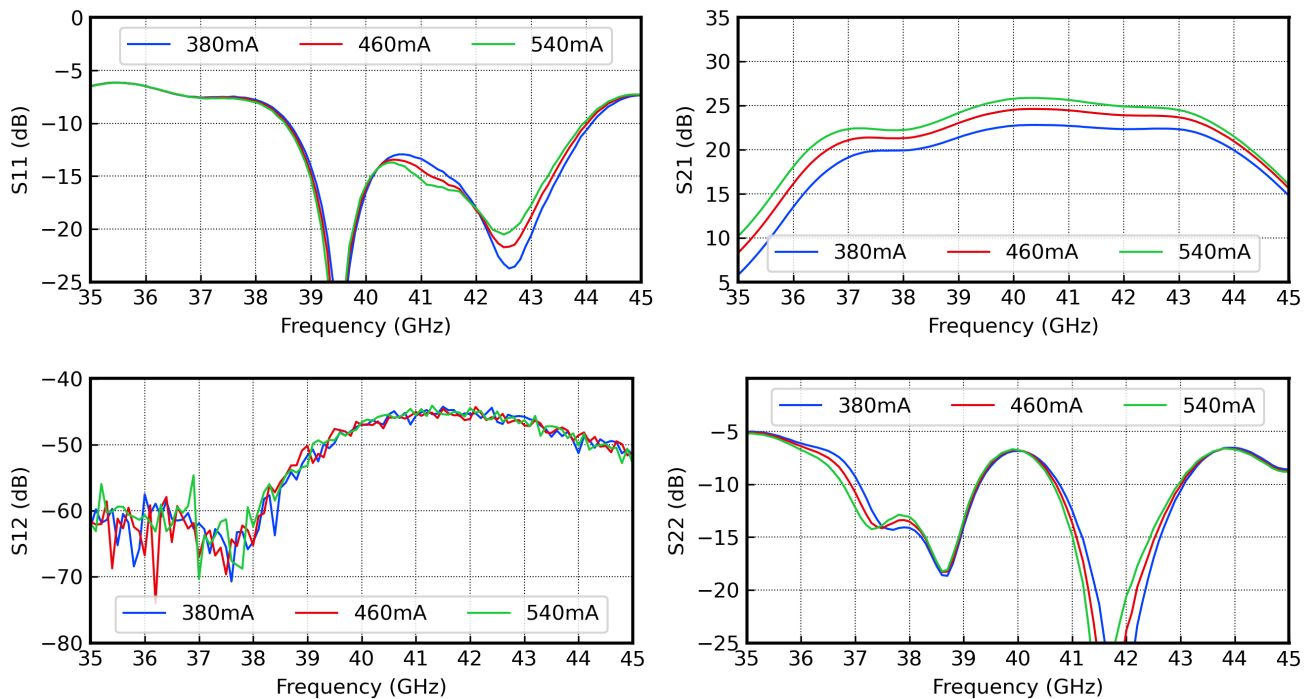
S Parameters versus frequency and Drain Voltage

Test conditions : IDq = 560mA, TB = 25°C



S Parameters versus frequency and Quiescent Drain Current

Test conditions : VD = 20V, TB = 25°C



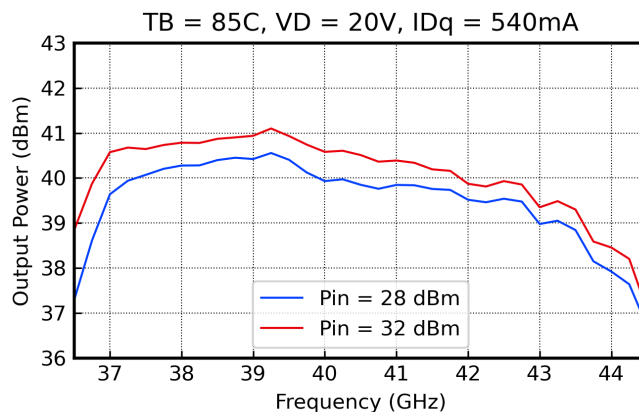
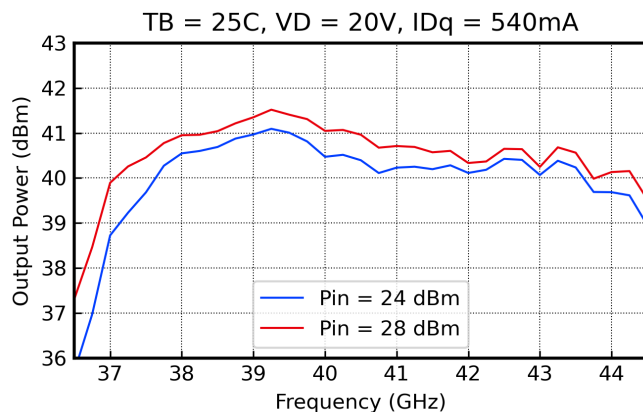
Typical Board Measurements : Large Signal Performance

Measurements reference plane is de-embedded at the wire-bondings planes of the RF lines.

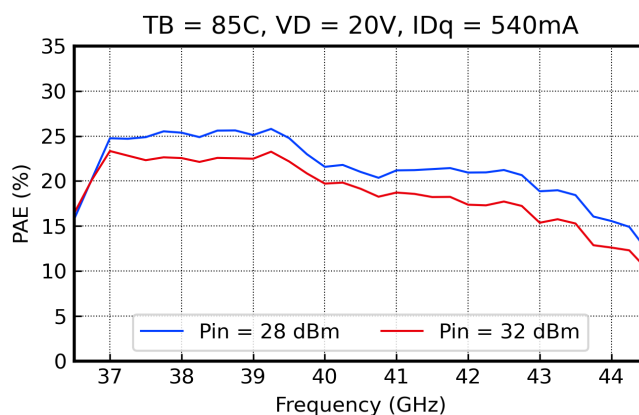
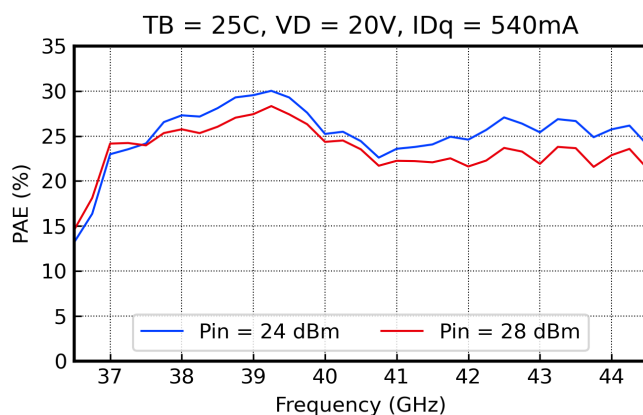
Performance versus frequency and temperature

Test conditions : $V_D = 20V$, $IDq = 540mA$, $TB = 25^\circ C / 85^\circ C$

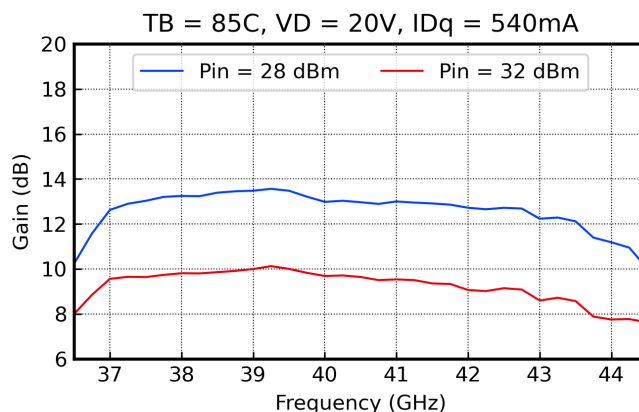
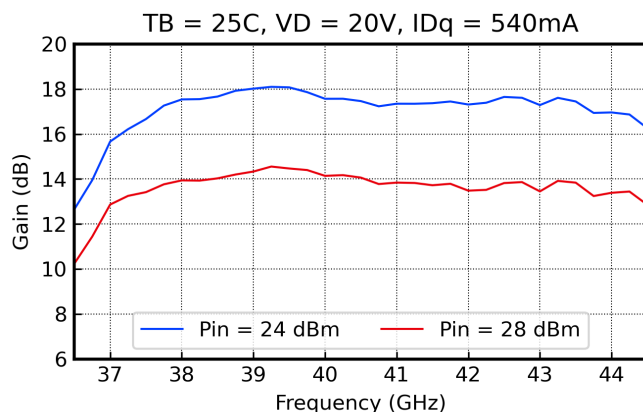
Output Power versus Frequency and Input Power



Power Added Efficiency versus Frequency and Input Power



Gain versus Frequency and Input Power



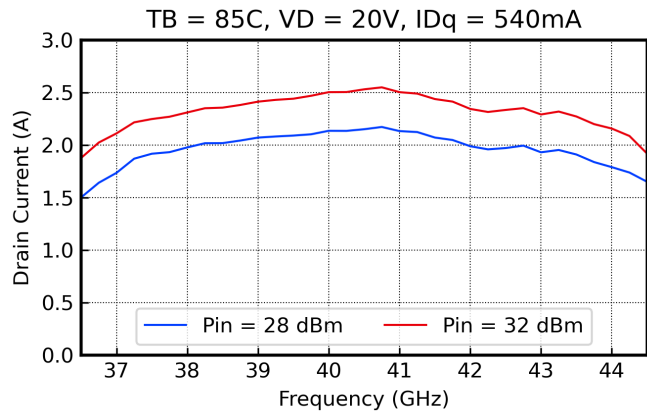
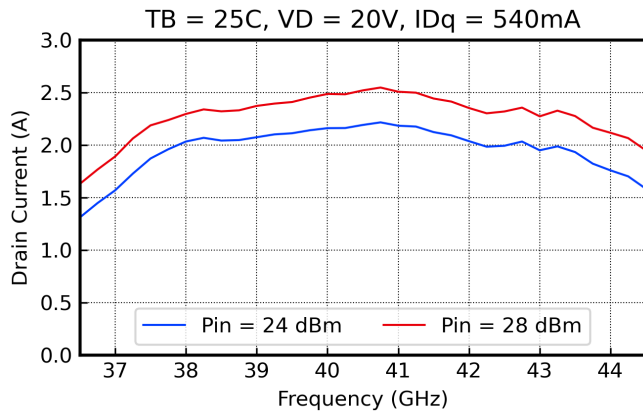
Typical Board Measurements : Large Signal Performance

Measurements reference plane is de-embedded at the wire-bondings planes of the RF lines.

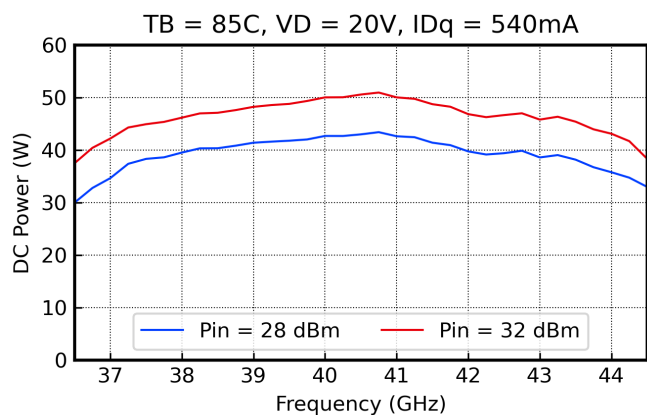
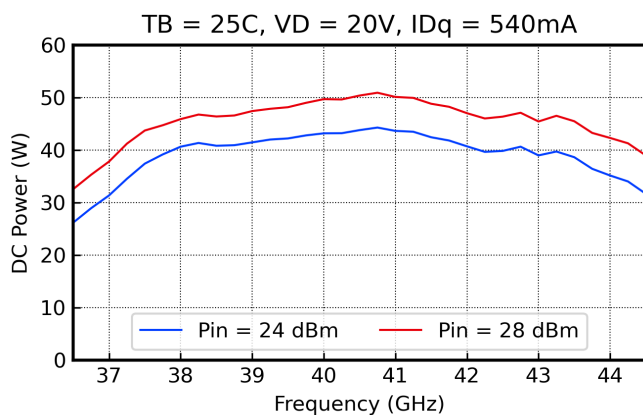
Performance versus frequency and temperature

Test conditions : $V_D = 20V$, $IDq = 540mA$, $TB = 25^\circ C / 85^\circ C$, Pin chosen at max PAE and Psat

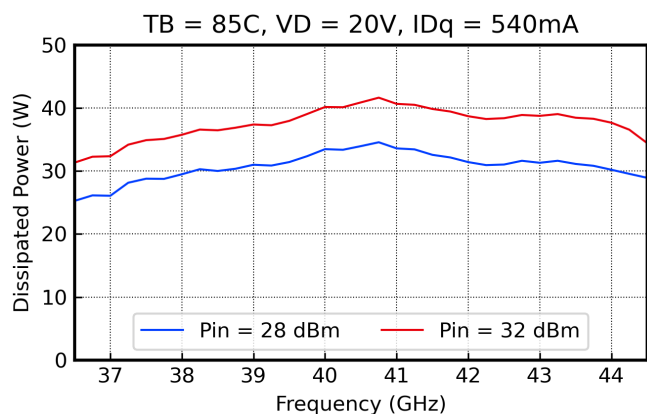
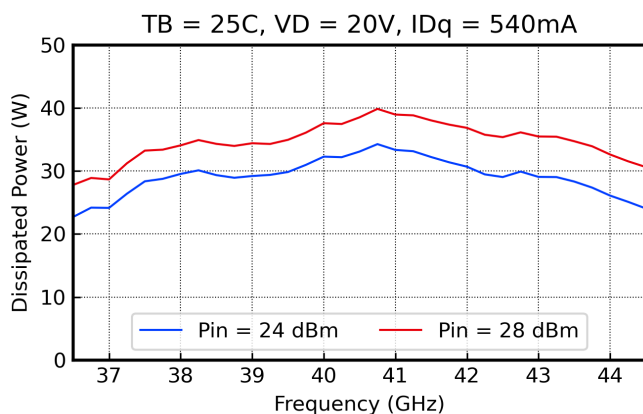
Drain Current versus Frequency and Input Power



DC Power Consumption versus Frequency and Input Power



Dissipated Power versus Frequency and Input Power



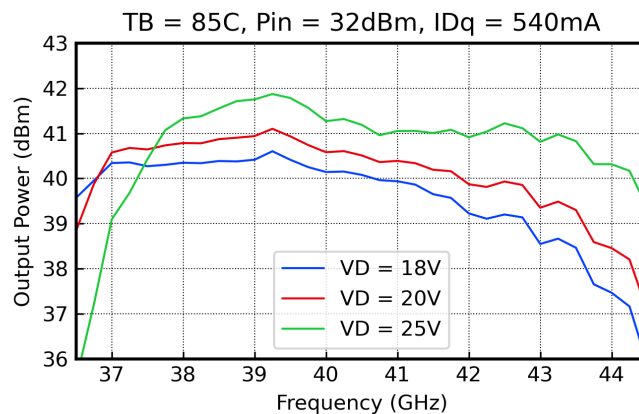
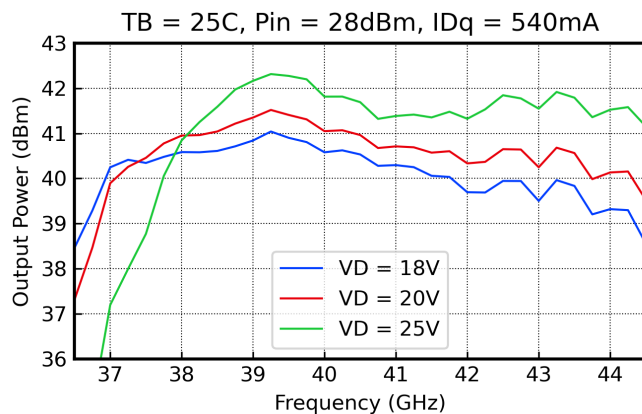
Typical Board Measurements : Large Signal Performance

Measurements reference plane is de-embedded at the wire-bondings planes of the RF lines.

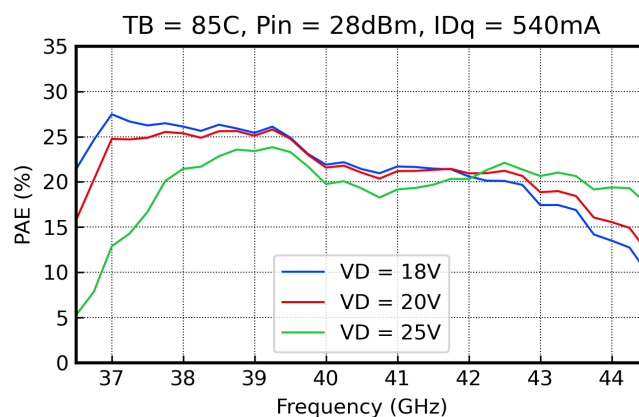
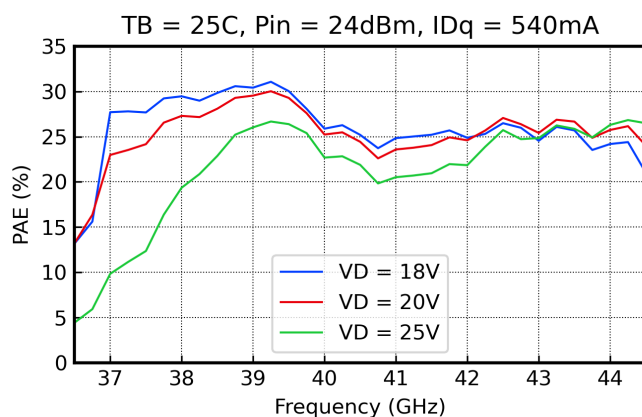
Performance versus frequency and temperature

Test conditions : $ID_q = 540\text{mA}$, $T_B = 25^\circ\text{C} / 85^\circ\text{C}$

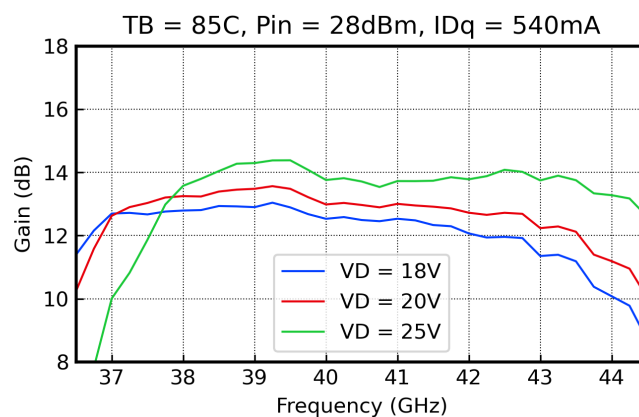
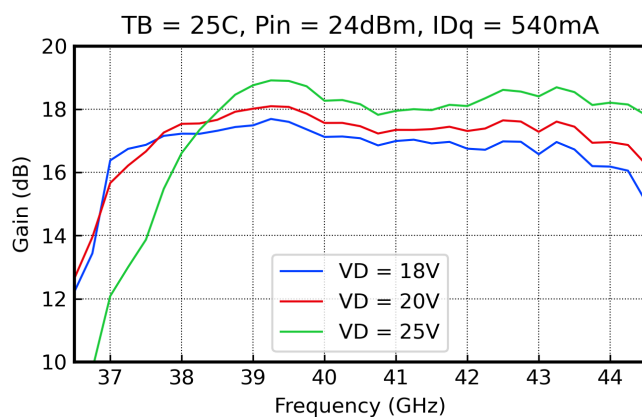
Output Power versus Frequency and Drain Voltage, Pin at Psat



Power Added Efficiency versus Frequency and Drain Voltage, Pin at max PAE



Gain versus Frequency and Drain Voltage, Pin at max PAE



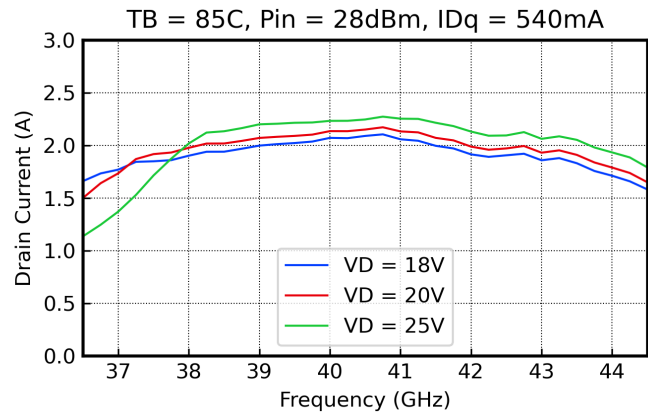
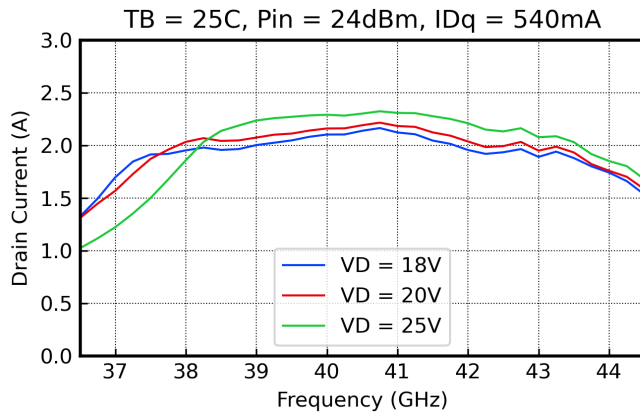
Typical Board Measurements : Large Signal Performance

Measurements reference plane is de-embedded at the wire-bondings planes of the RF lines.

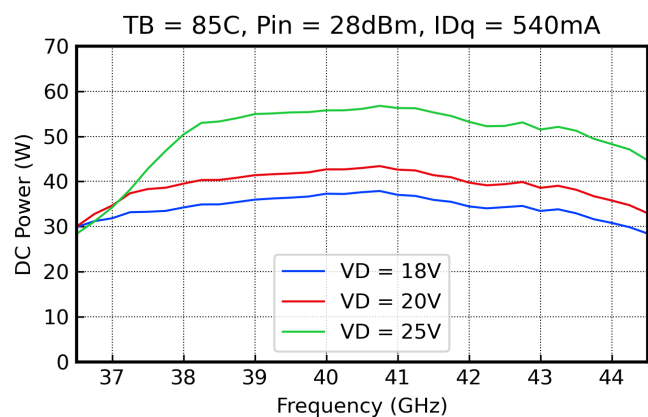
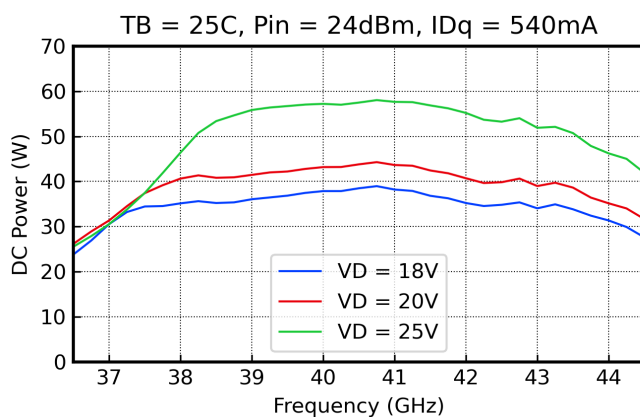
Performance versus frequency and temperature

Test conditions : $IDq = 540mA$, $TB = 25^{\circ}C / 85^{\circ}C$

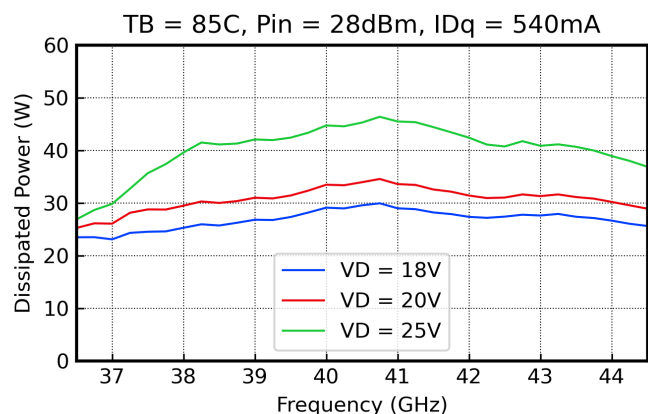
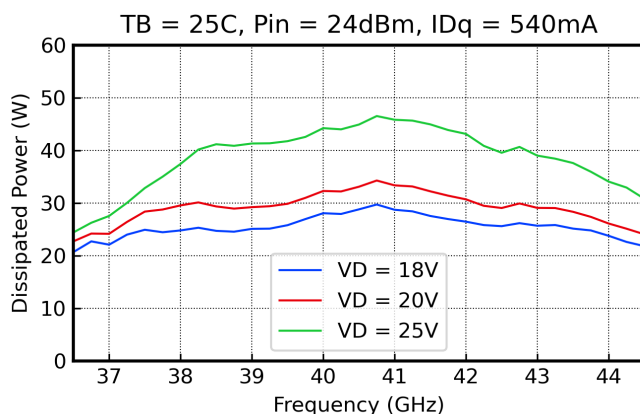
Drain Current versus Frequency and Drain Voltage, Pin at max PAE



DC Power Consumption versus Frequency and Drain Voltage, Pin at max PAE



Dissipated Power versus Frequency and Drain Voltage, Pin at max PAE



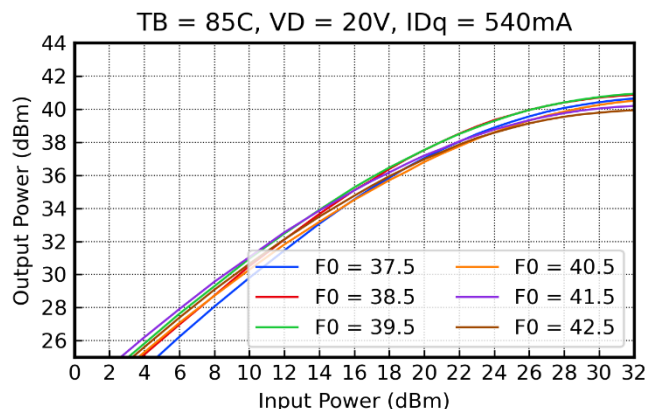
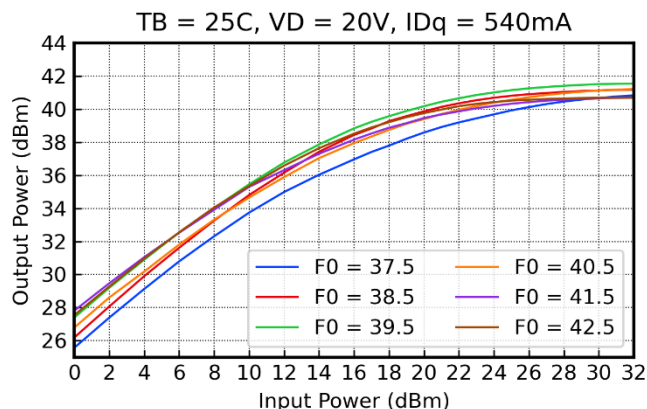
Typical Board Measurements : Large Signal Performance

Measurements reference plane is de-embedded at the wire-bondings planes of the RF lines.

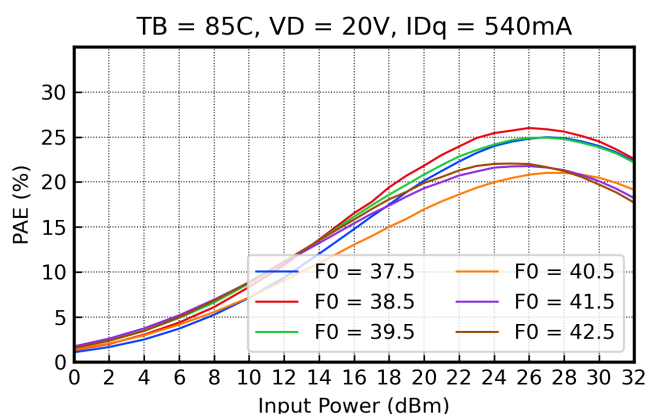
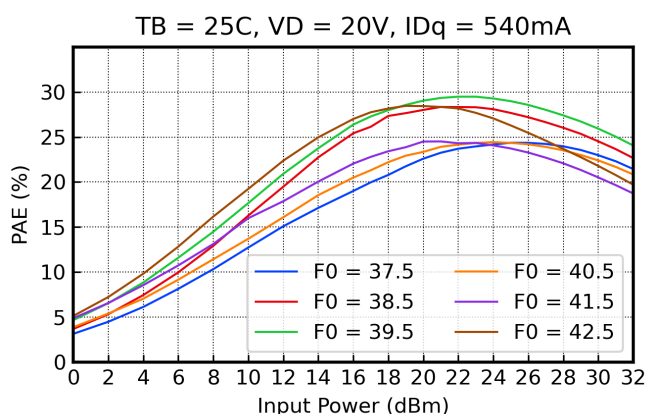
Performance versus frequency and temperature

Test conditions : $I_{Dq} = 540\text{mA}$, $T_B = 25^\circ\text{C} / 85^\circ\text{C}$

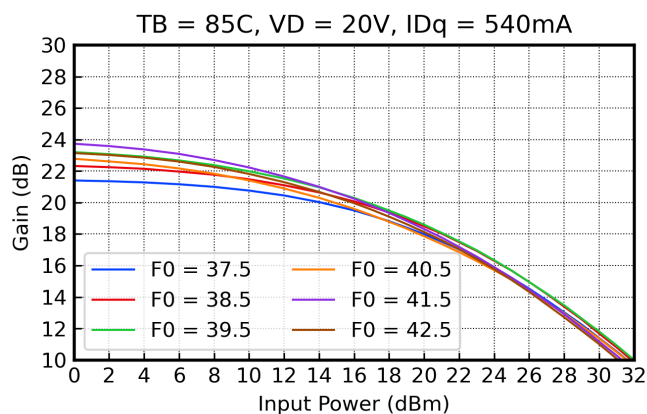
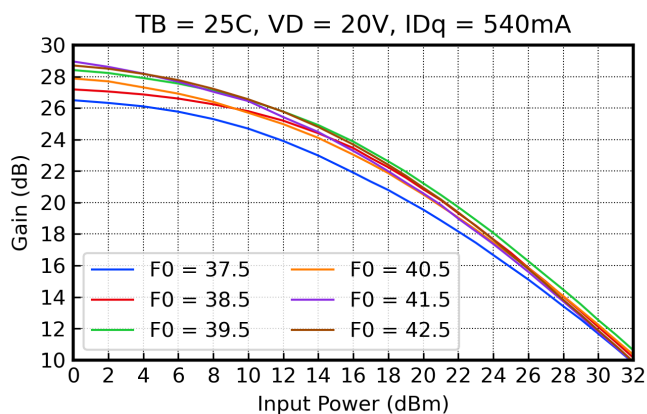
Output Power versus Input Power and Frequency



Power Added Efficiency versus Input Power and Frequency



Gain versus Input Power and Frequency



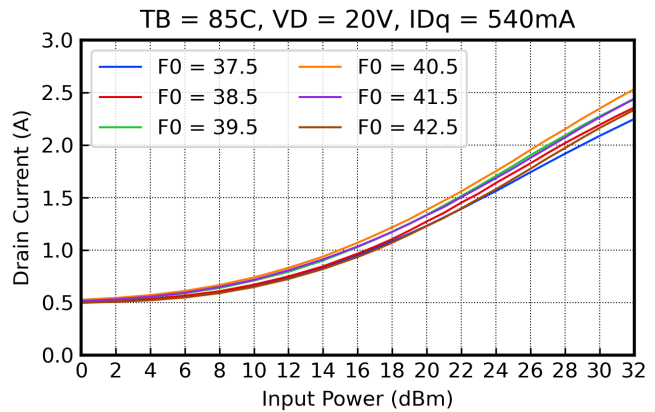
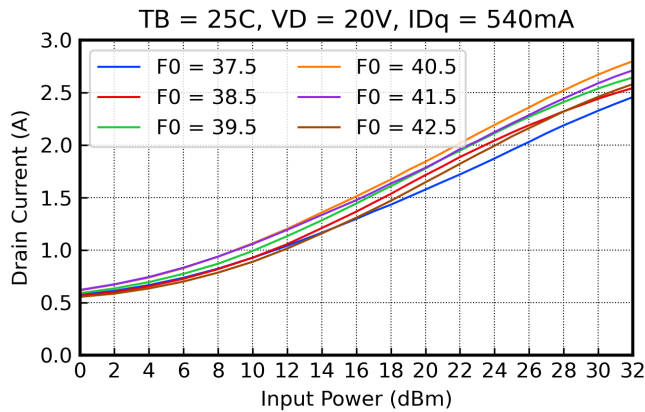
Typical Board Measurements : Large Signal Performance

Measurements reference plane is de-embedded at the wire-bondings planes of the RF lines.

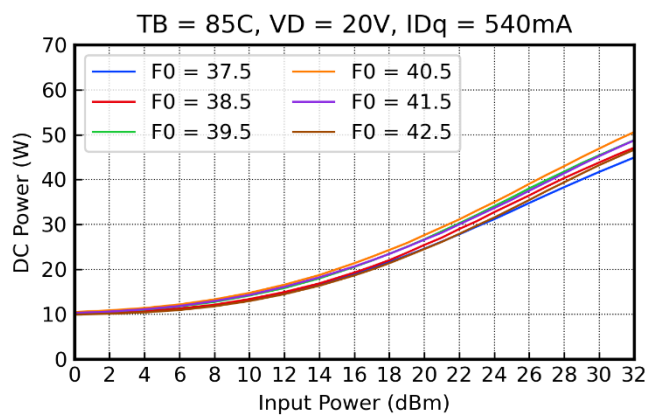
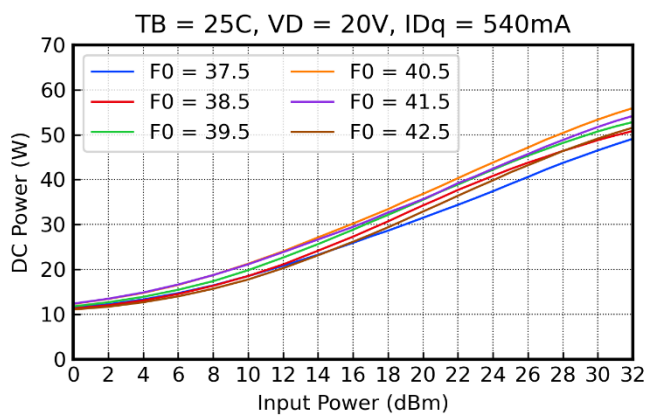
Performance versus frequency and temperature

Test conditions : $ID_q = 540\text{mA}$, $TB = 25^\circ\text{C} / 85^\circ\text{C}$

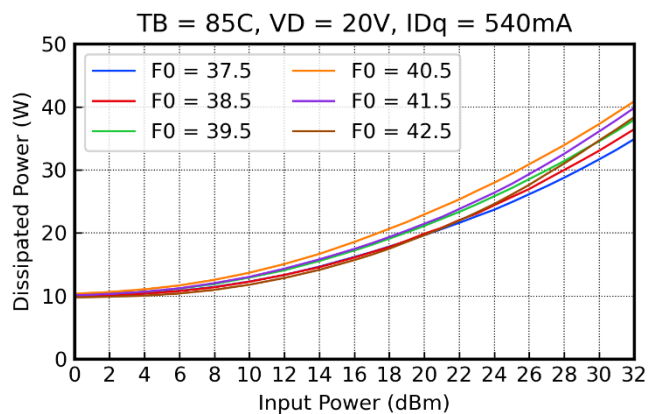
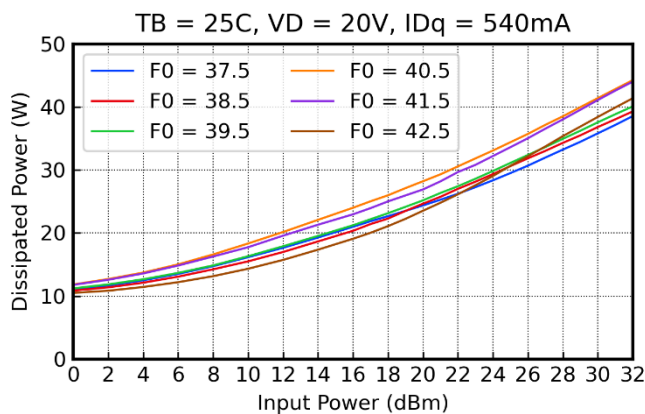
Drain Current versus Input Power and Frequency



DC Power Consumption versus Input Power and Frequency



Dissipated Power versus Input Power and Frequency



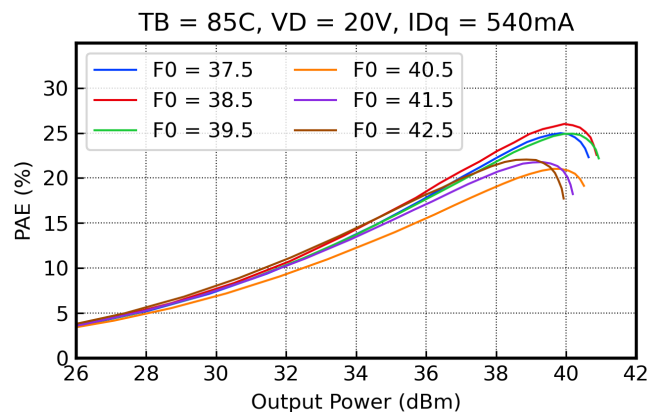
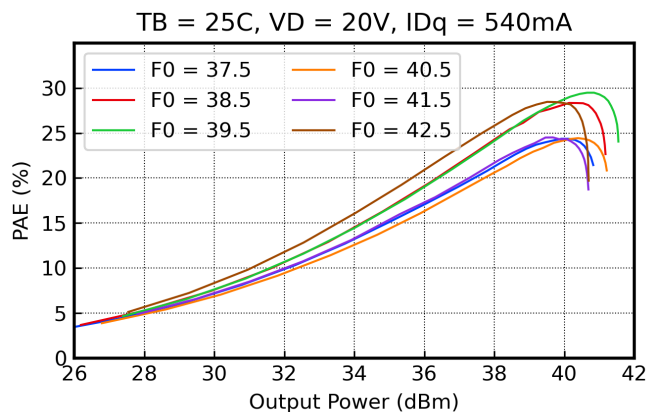
Typical Board Measurements : Large Signal Performance

Measurements reference plane is de-embedded at the wire-bondings planes of the RF lines.

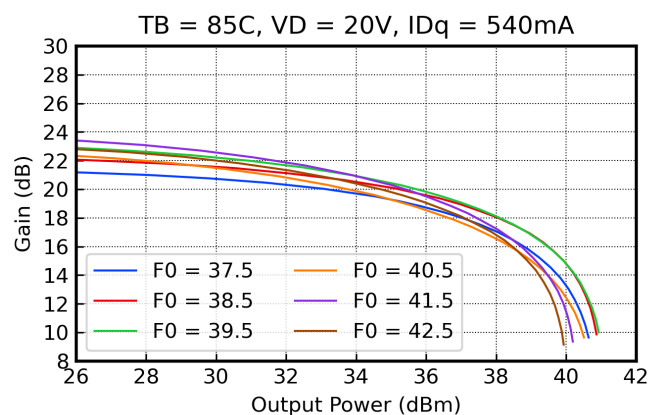
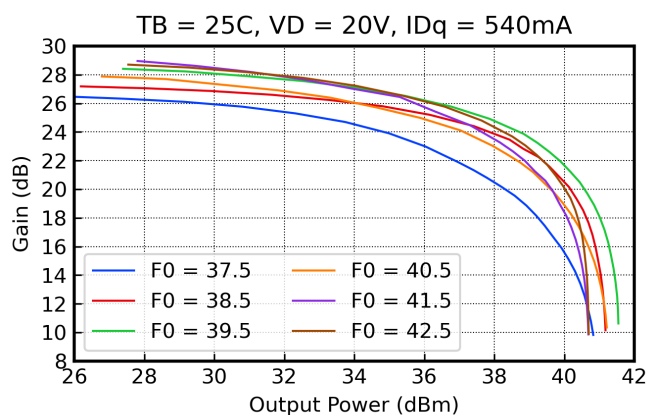
Performance versus frequency and temperature

Test conditions : $ID_q = 540\text{mA}$, $T_B = 25^\circ\text{C} / 85^\circ\text{C}$

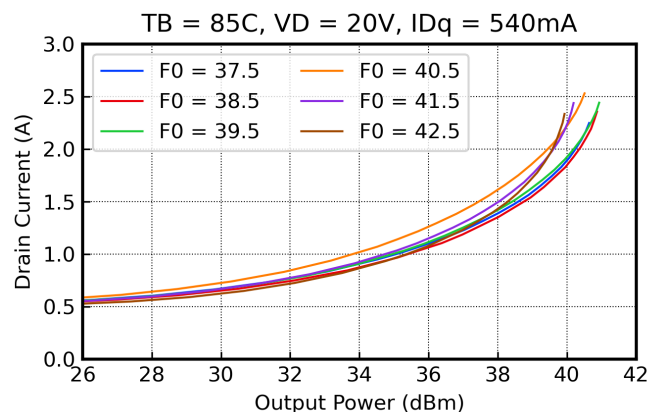
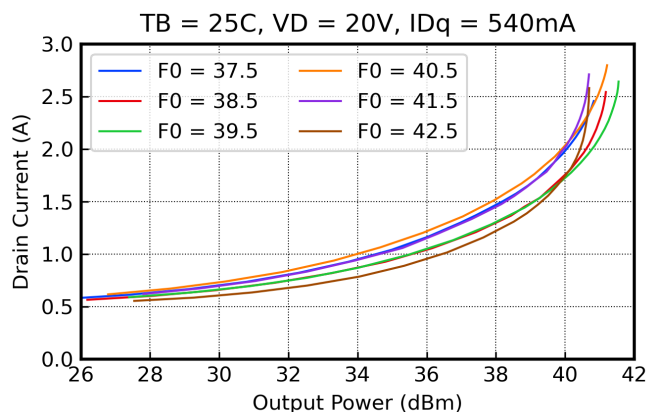
Power Added Efficiency versus Output Power and Frequency



Gain versus Output Power and Frequency



Drain Current versus Output Power and Frequency



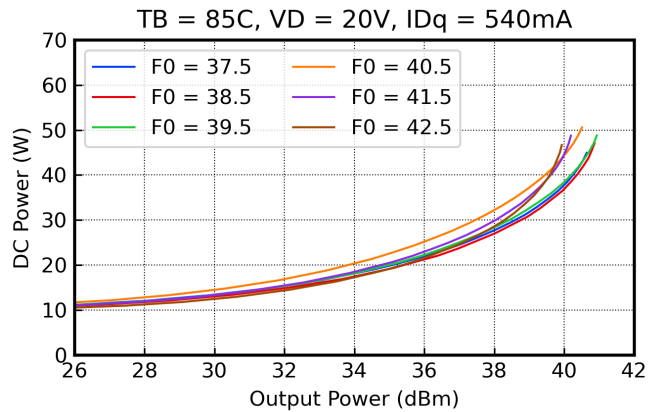
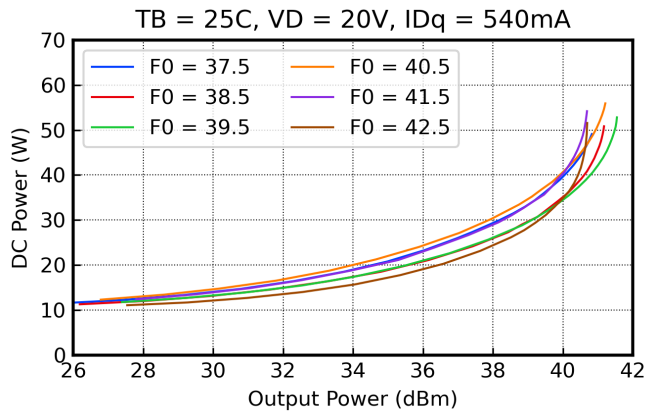
Typical Board Measurements : Large Signal Performance

Measurements reference plane is de-embedded at the wire-bondings planes of the RF lines.

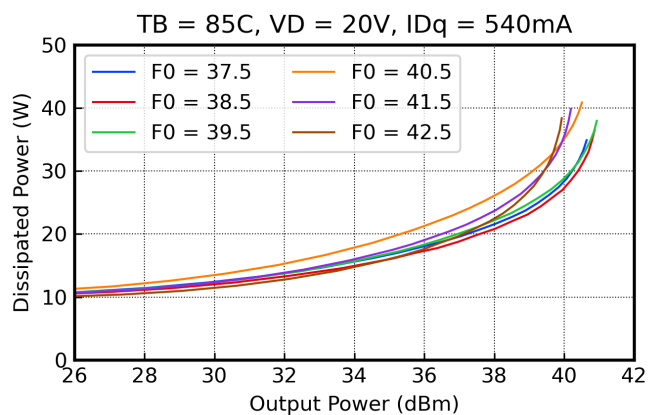
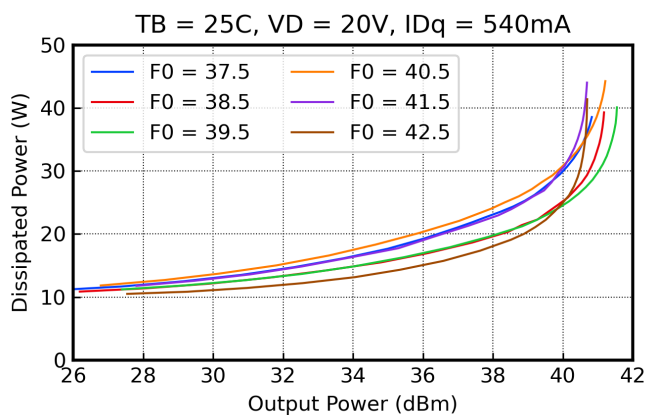
Performance versus frequency and temperature

Test conditions : $V_D = 20V$, $I_{Dq} = 540mA$, $T_B = 25^\circ C / 85^\circ C$

DC Power Consumption versus Output Power and Frequency



Dissipated Power versus Output Power and Frequency

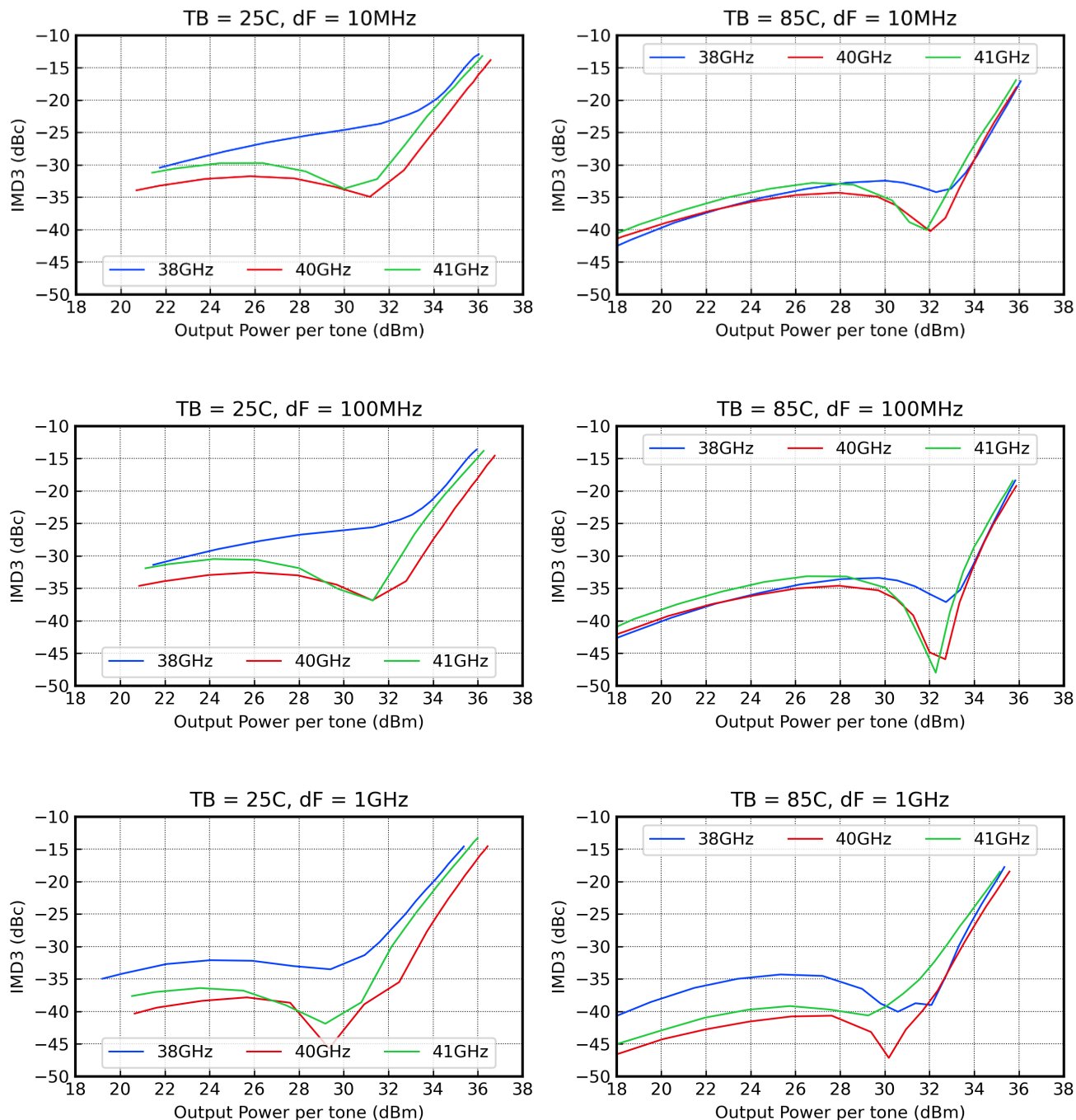


Typical Board Measurements : Two Tone Large Signal Performance

Measurements reference plane is de-embedded at the wire-bondings planes of the RF lines.
Tone spacing is 100MHz, unless stated otherwise

IMD3 versus Output Power and Central Frequency

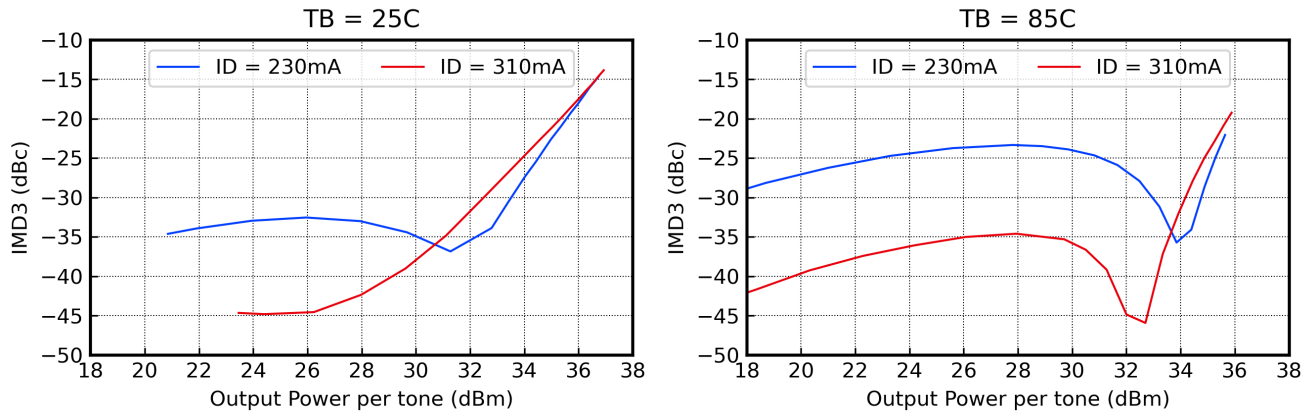
Test conditions : $V_D = 20V$, $T_B = 25^\circ C$ & $I_{DQ} = 230mA$, $T_B = 85^\circ C$ & $I_{DQ} = 310mA$



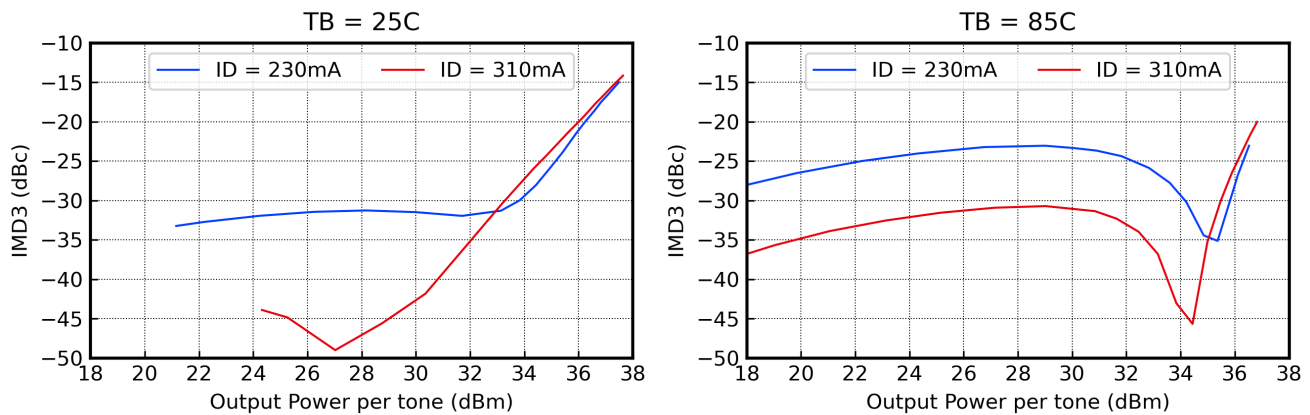
Typical Board Measurements : Two Tone Large Signal Performance

Measurements reference plane is de-embedded at the wire-bondings planes of the RF lines.
Tone spacing is 100MHz, unless stated otherwise

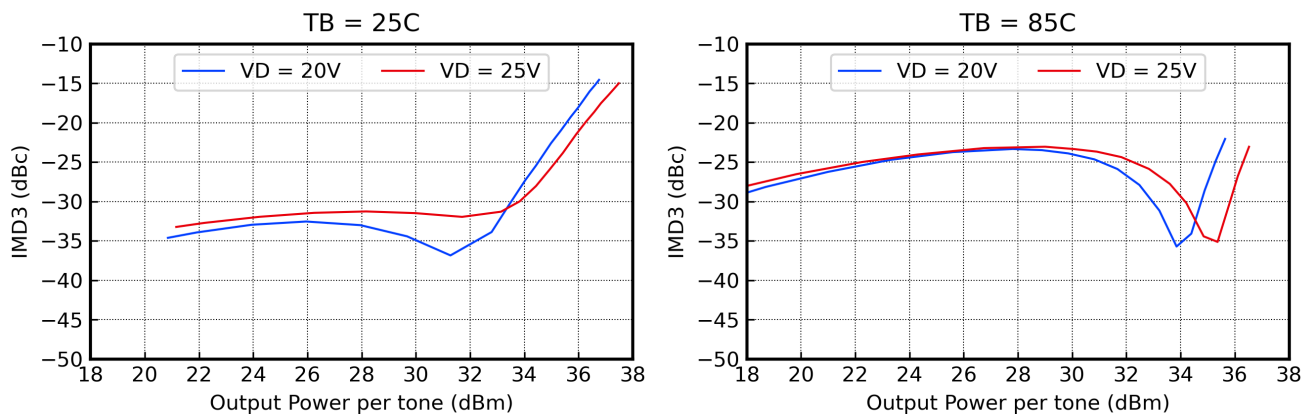
IMD3 versus Output Power and Quiescent Current
Test conditions : F0 = 40GHz, VD = 20V, TB = 25°/85°C



IMD3 versus Output Power and Quiescent Current
Test conditions : F0 = 40GHz, VD = 25V, TB = 25°/85°C



IMD3 versus Output Power and Drain Voltage
Test conditions : F0 = 40GHz, IDq = 230mA, TB = 25°/85°C

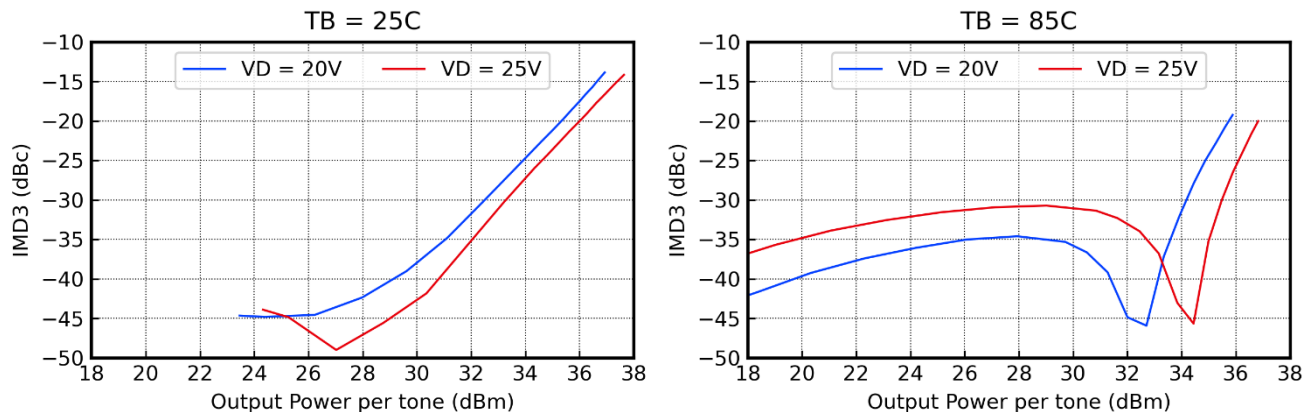


Typical Board Measurements : Two Tone Large Signal Performance

Measurements reference plane is de-embedded at the wire-bondings planes of the RF lines.
Tone spacing is 100MHz, unless stated otherwise

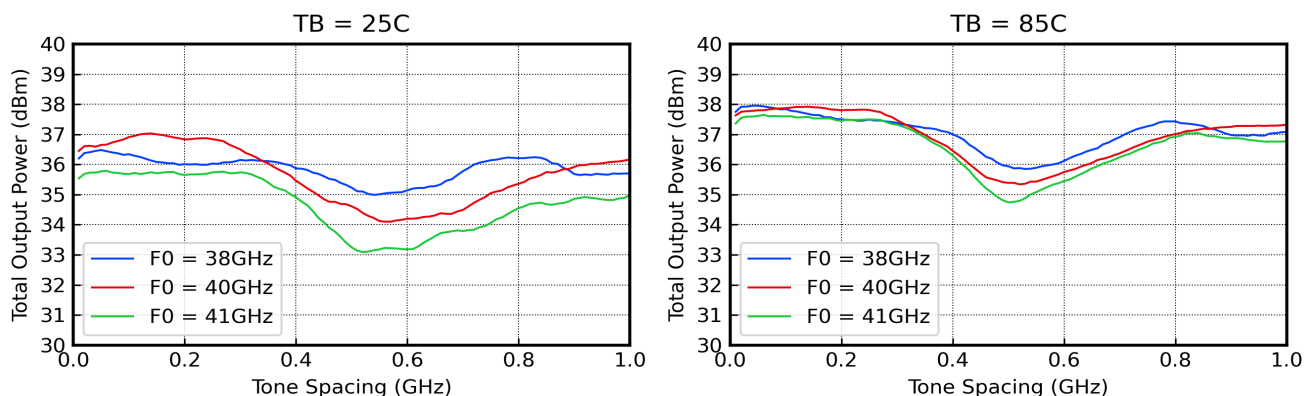
IMD3 versus Output Power and Drain Voltage

Test conditions : $F_0 = 40\text{GHz}$, $ID_q = 310\text{mA}$, $TB = 25^\circ/85^\circ\text{C}$



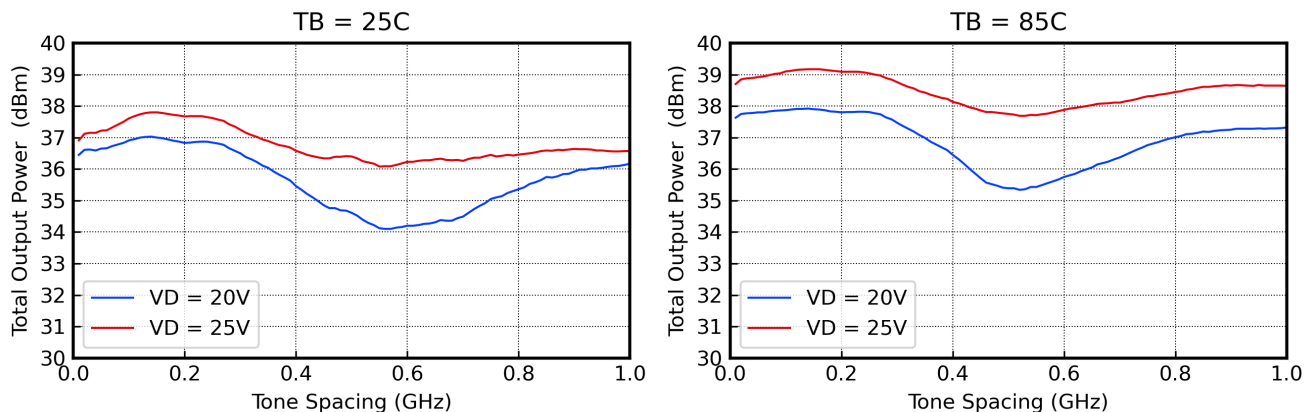
IMD3 versus Tone Spacing and Central Frequency

Test conditions : $VD = 20\text{V}$, $ID_q = 310\text{mA}$, $TB = 25^\circ/85^\circ\text{C}$



IMD3 versus Tone Spacing and Drain Voltage

Test conditions : $F_0 = 40\text{GHz}$, $ID_q = 310\text{mA}$, $TB = 25^\circ/85^\circ\text{C}$

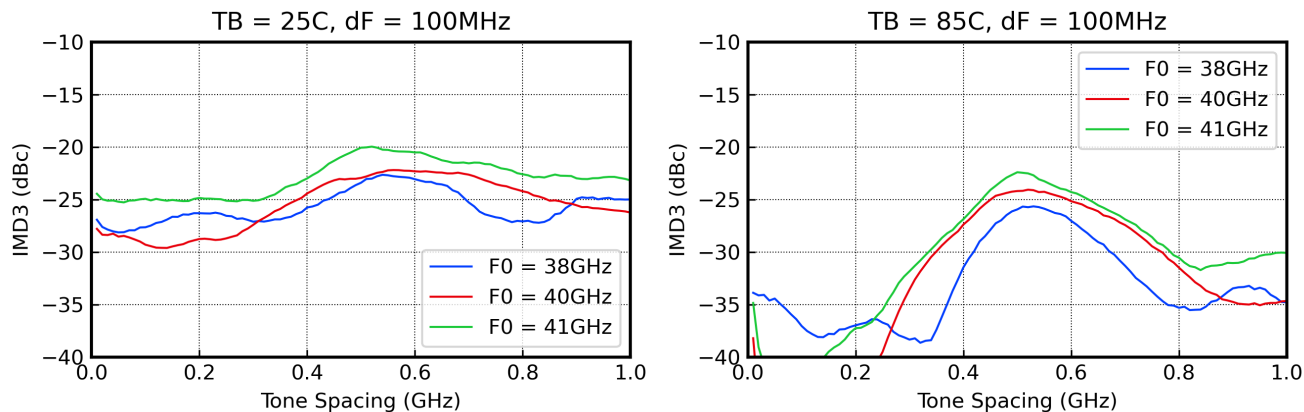


Typical Board Measurements : Two Tone Large Signal Performance

Measurements reference plane is de-embedded at the wire-bondings planes of the RF lines.
Tone spacing is 100MHz, unless stated otherwise

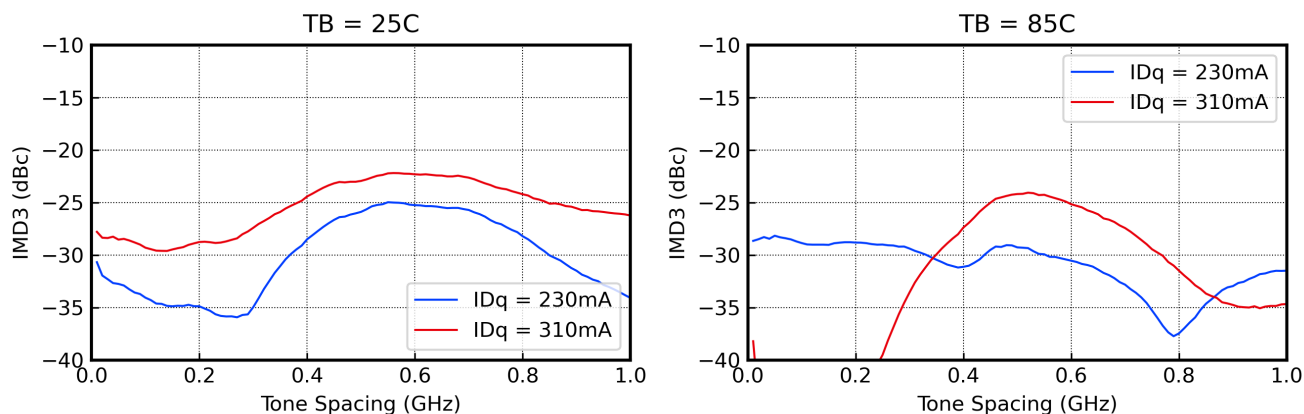
IMD3 at 36dBm Total Output Power, versus Tone Spacing and Central Frequency

Test conditions : $I_{Dq} = 310\text{mA}$, $V_D = 20\text{V}$, $T_B = 25^\circ/85^\circ\text{C}$



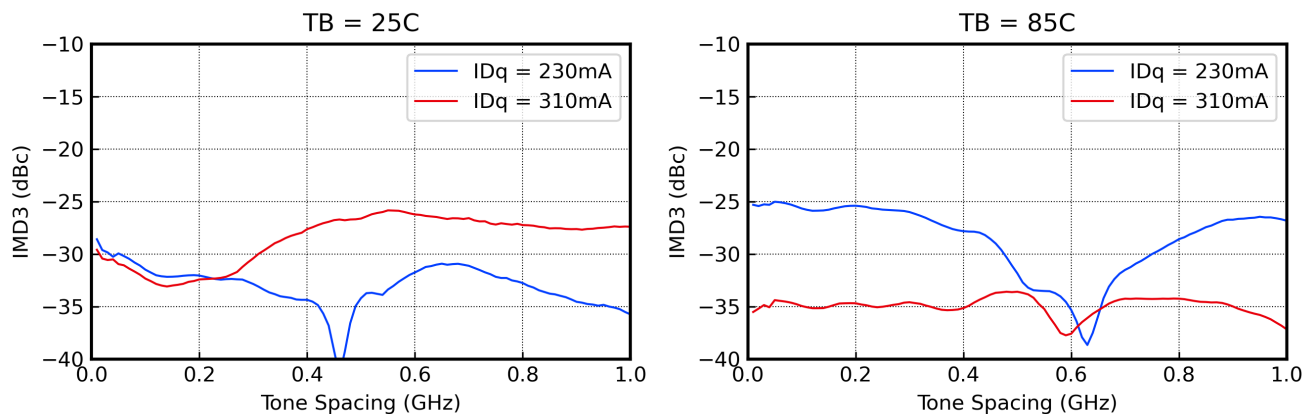
IMD3 at 36dBm Total Output Power, versus Tone Spacing and Quiescent Current

Test conditions : $F_0 = 40\text{GHz}$, $V_D = 20\text{V}$,



IMD3 at 36dBm Total Output Power, versus Tone Spacing and Quiescent Current

Test conditions : $F_0 = 40\text{GHz}$, $V_D = 25\text{V}$,



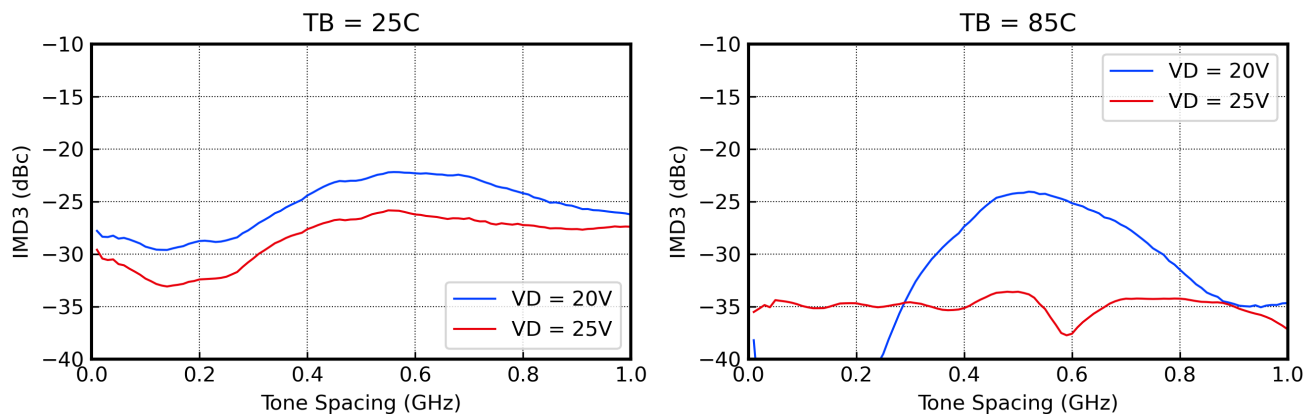
Typical Board Measurements : Two Tone Large Signal Performance

Measurements reference plane is de-embedded at the wire-bondings planes of the RF lines.

Tone spacing is 100MHz, unless stated otherwise

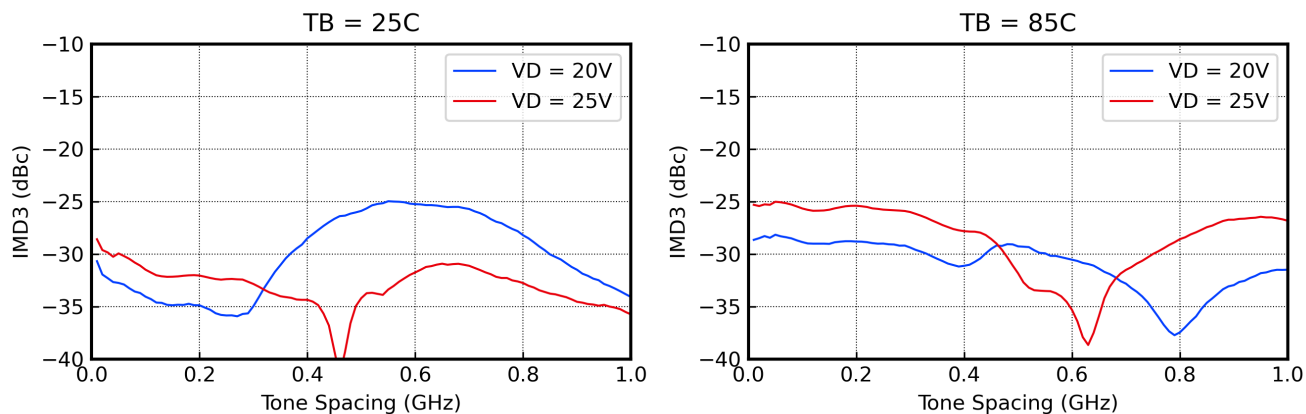
IMD3 at 36dBm Total Output Power, versus Tone Spacing and Drain Voltage

Test conditions : $F_0 = 40\text{GHz}$, $ID_q = 310\text{mA}$,



IMD3 at 36dBm Total Output Power, versus Tone Spacing and Drain Voltage

Test conditions : $F_0 = 40\text{GHz}$, $ID_q = 230\text{mA}$,



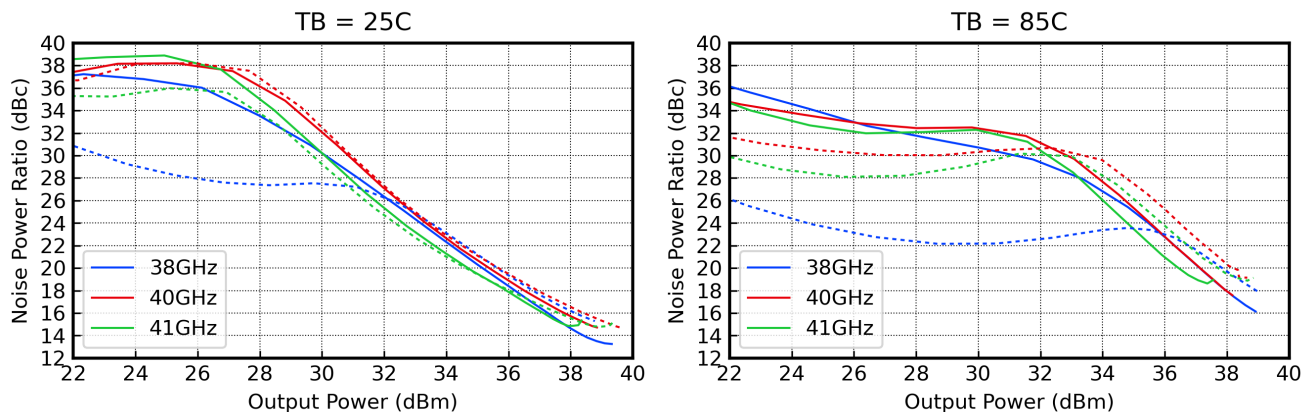
Typical Board Measurements : Noise Power Ratio

NPR Signal : 40MHz Signal Bandwidth, 10% Notch

Measurements reference plane is de-embedded at the wire-bondings planes of the RF lines.

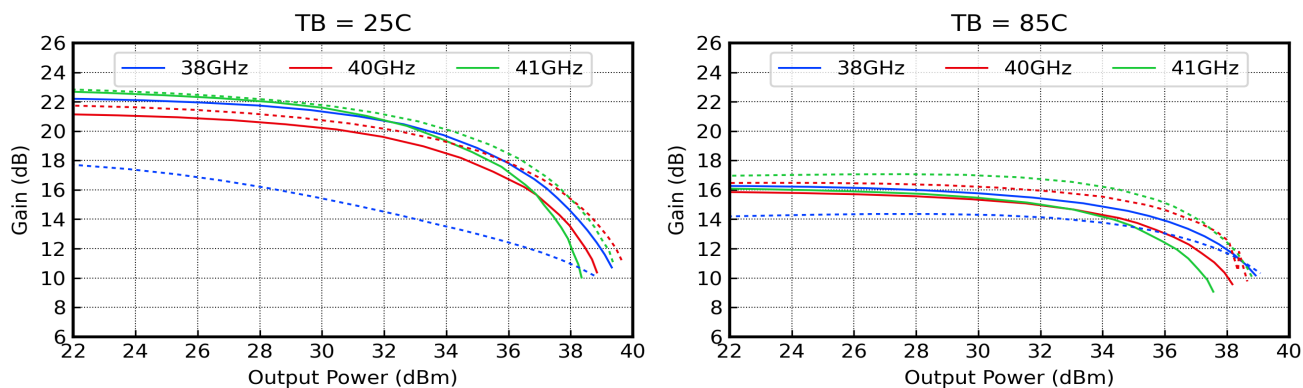
NPR versus Output Power and Central Frequency

Test conditions : IDq = 310mA, TB = 25°/85°C, solid line VD = 20V, dashed line VD = 25V



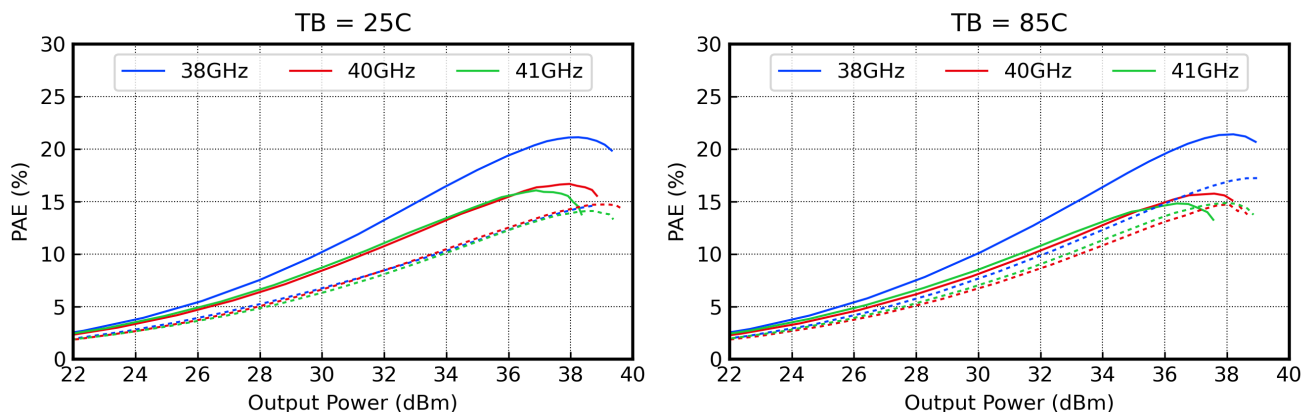
Gain versus Output Power and Central Frequency

Test conditions : IDq = 310mA, TB = 25°/85°C, solid line VD = 20V, dashed line VD = 25V



PAE versus Output Power and Central Frequency

Test conditions : IDq = 310mA, TB = 25°/85°C, solid line VD = 20V, dashed line VD = 25V



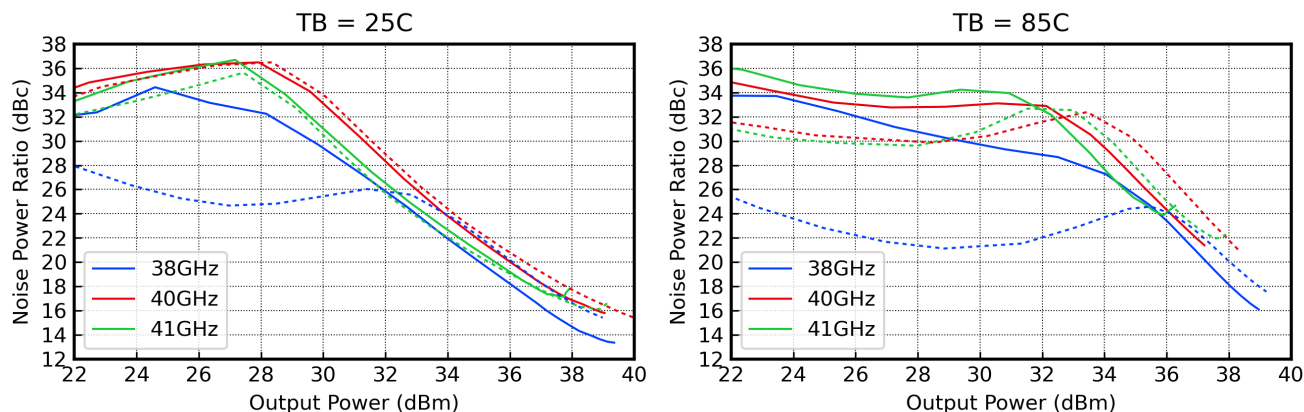
Typical Board Measurements : Noise Power Ratio

NPR Signal : 1GHz Signal Bandwidth, 10% Notch

Measurements reference plane is de-embedded at the wire-bondings planes of the RF lines.

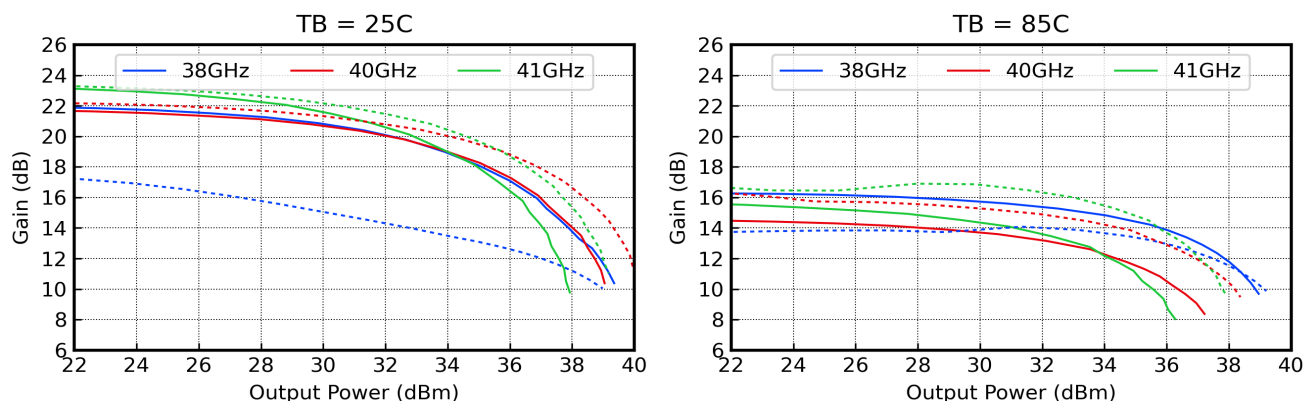
NPR versus Output Power and Central Frequency

Test conditions : IDq = 310mA, TB = 25°/85°C, solid line VD = 20V, dashed line VD = 25V



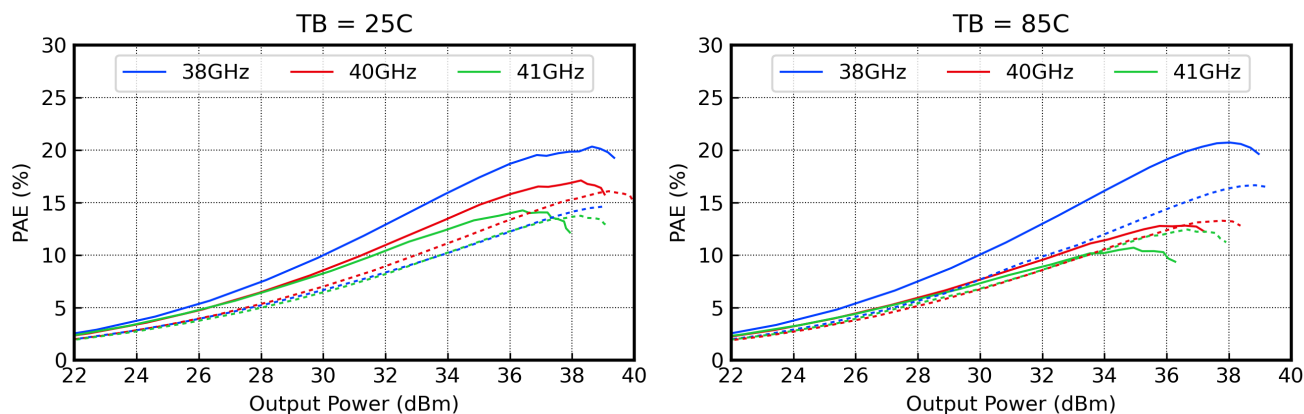
Gain versus Output Power and Central Frequency

Test conditions : IDq = 310mA, TB = 25°/85°C, solid line VD = 20V, dashed line VD = 25V

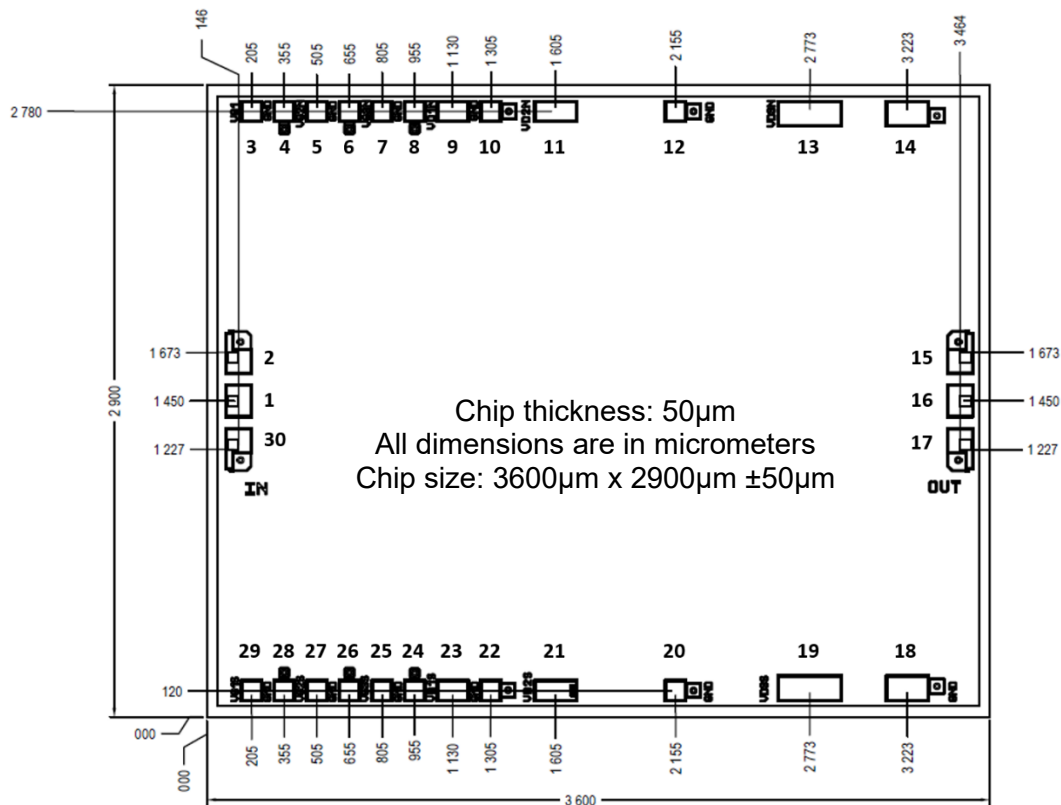


PAE versus Output Power and Central Frequency

Test conditions : IDq = 310mA, TB = 25°/85°C, solid line VD = 20V, dashed line VD = 25V

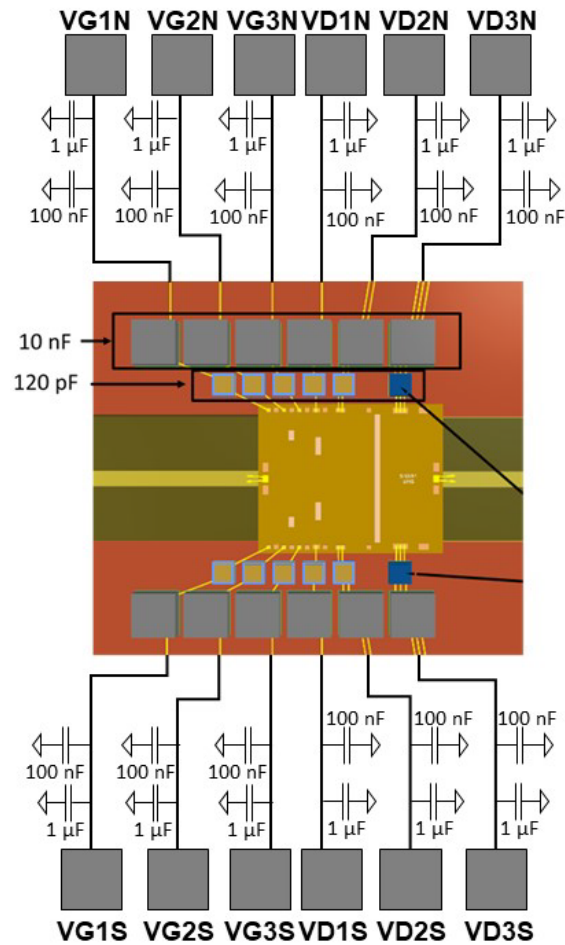


Mechanical Data



PAD Number	Name	Description	Pad size
1	RF IN	Input RF port	186µm x 105µm
3	G12	DC Gate voltage, 1 st & 2 nd stage, North	96µm x 96µm
5	G3	DC Gate voltage 3 rd stage, North	96µm x 96µm
7	G4	DC Gate voltage 4 th stage, North	96µm x 96µm
9	D12	DC Drain voltage, 1 st & 2 nd stage, North	146µm x 96µm
11	D3	DC Drain voltage 3 rd stage, North	196µm x 96µm
13	D4	DC Drain voltage 4 th stage, North	296µm x 116µm
16	RF OUT	Output RF port	118 µm x 146 µm
19	D4	DC Drain voltage 4 th stage, South	296µm x 116µm
21	D3	DC Drain voltage 3 rd stage, South	196µm x 96µm
23	D12	DC Drain voltage, 1 st & 2 nd stage, South	146µm x 96µm
25	G4	DC Gate voltage 4 th stage, South	96µm x 96µm
27	G3	DC Gate voltage 3 rd stage, South	96µm x 96µm
29	G12	DC Gate voltage, 1 st & 2 nd stage, South	96µm x 96µm
2,4,6,8,10,12,14,15,17,18,20,22,24,26,28,30	GND	Ground	96µm x 96µm

Recommended Assembly Plan



4 levels of decoupling capacitor have been used, 2 on the tab and 2 on the board. The first level is composed of 120 pF chip capacitors, the second level is composed of 10nF chip capacitors, the third level is composed of 100nF SMD 1210 capacitors and the fourth stage is composed of 1μF SMD 1206 capacitors. The first two levels should be as close as possible to the die.

ESD Sensitivity

Parameter	Classification	Standard
Human Body Model (HBM)	1A	ANSI/ESDA/JEDEC - JS-001

Recommended reflow process assembly

Refer to the application note AN0001 available at <https://www.ums-rf.com> for die attach.

Recommended environmental management

UMS products are compliant with the regulation in particular with the directives RoHS N°2011/65 and REACH N°1907/2006. More environmental data are available in the application note AN0019 also available at <https://www.ums-rf.com>.

Recommended ESD management

Refer to the application note AN0020 available at <https://www.ums-rf.com> for ESD sensitivity and handling recommendations for the UMS products.

Maturity Level

Maturity Level	Product status	Documentation	Reliability	Usage in a system
Engineering Sample (ES)	Design may change	Advanced Information	The design is within the recommended temperature, current and voltage ranges as regards the technology used.	Engineering demonstrator

Sampling request reference

Die: ES-CHA8454-99F

Contact us

Web site: <https://www.ums-rf.com>

e.mail: mktsales@ums-rf.com

Phone: +33 (1) 69 86 32 00 (France)
+1 (781) 791-5078 (USA)
+65 9298 8316 (Singapore)